Notice of References Cited Application/Control No. 10/727,594 Examiner JOHN J. LEE Applicant(s)/Patent Under Reexamination DELBREIL ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,020,701	03-2006	Gelvin et al.	370/390
*	В	US-2002/0150228	10-2002	Umeda et al.	455/403
*	С	US-2004/0129890	07-2004	Berman et al.	250/380
	,D	US-		·	
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-		·	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P.					
	Q					
	R					
	s				***************************************	
	Т			****		

NON-PATENT DOCUMENTS

		NON-PATENT DOCUMENTS
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.